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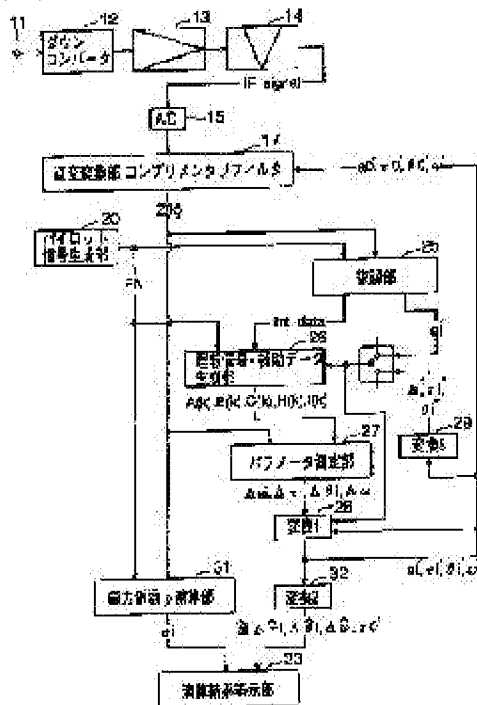
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(54) WAVEFORM QUALITY MEASURING METHOD FOR CDMA SIGNAL



(57)Abstract:

PROBLEM TO BE SOLVED: To improve measurement precision.

SOLUTION: A measurement signal $Z(k)$ of a base-band from an orthogonal conversion part 17 is demodulated by the PN code of a pilot signal in a demodulation part 25. The demodulation bit string and amplitude a_i is detected. An ideal signal R_i is generated from them and the PN code. Auxiliary data A, B, C, H and I for solving approximated simultaneous equations obtaining parameters for minimizing the square of the error of R_i and $Z(k)$ are obtained (26). Then, the simultaneous equations are solvent from them and $Z(k)$. Parameters Δa_i , $\Delta \tau_i$, $\Delta \theta_i$ and $\Delta \omega$ are estimated (27). Thus, $Z(k)$, R_i , A, B, C, H and I are corrected by the finding of parameter estimation is repeated again until the parameter is optimized. Then, an electric coefficient p_i is obtained by $Z(k)$ and PN.